

Notice of References Cited

Application/Control No.

10/502,004

Applicant(s)/Patent Under
Reexamination
READ, DALE

Examiner

Mary C. Jacob

Art Unit

2123

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,791,549	09-2004	Hubrecht et al.	345/473
*	C	US-6,725,184	04-2004	Gadh et al.	703/2
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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